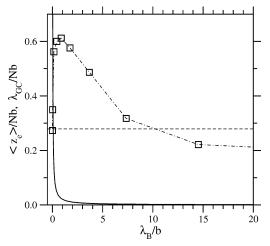
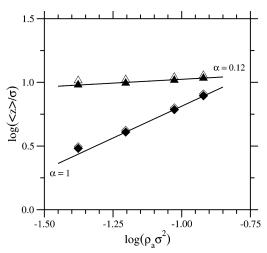
## CORRECTIONS

**Christian Seidel**: Strongly Stretched Polyelectrolyte Brushes. Volume 36, Number 7, April 8, 2003, pp 2536–2543.

Because of a numerical error, unfortunately the simulations were effectively carried out at Bjerrum lengths different from those given in the paper. In fact strongly stretched brushes were simulated not at  $\lambda_{\rm B}=0.1\sigma$  but instead at  $\lambda_{\rm B}{\approx}2\sigma$ . In addition to that, the numerical error causes a weak dependence of the real Bjerrum length on grafting density that has some influence on the exact value of stretching in the strongly elongated regime at small anchoring densities. Figure 1 and Figure 4 should have appeared as shown here. Maximum stretching occurs at  $\lambda_{\rm B}\approx b$ . Although at intermediate coupling strength the slope of  $log(\langle z_m\rangle)$  vs  $log(\rho_a)$  is reduced from 0.2 to 0.12, the slight brush height



**Figure 1.** Average height of chain ends  $\langle z_{\rm e} \rangle$  (squares) and Gouy–Chapman length  $\lambda_{\rm GC}$  (solid line), both rescaled with the contour length Nb (N = 20), vs Bjerrum length  $\lambda_{\rm B}$  at grafting density  $\rho_{\rm a}\sigma^2=0.02$ . The dashed line indicates  $\langle z_{\rm e} \rangle$  of an identical system of uncharged chains.



**Figure 4.** Average brush height  $\langle z_{\rm m} \rangle$  (filled symbols) and average counterion height  $\langle z_{\rm ci} \rangle$  (empty symbols) of completely charged polyelectrolyte brushes vs anchoring density both for  $\lambda_{\rm B}=\sigma$  (triangles, new results) and  $\lambda_{\rm B}\approx 14\sigma$  (diamonds). Error bars are smaller than symbol size.

variation upon lateral compression, meanwhile also detected in experiments, is still in agreement with the theoretical predictions of the nonlinear osmotic brush regime.<sup>1</sup>

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## **References and Notes**

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